



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AONS36344**

**30V N-Channel MOSFET**

### General Description

- Trench Power MOSFET technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	83A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 3.28mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 5.15mΩ

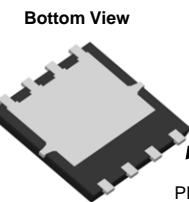
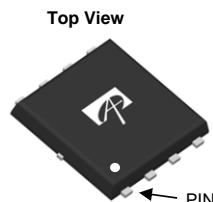
### Applications

- DC/DC Converters in Computing, Servers, and POL

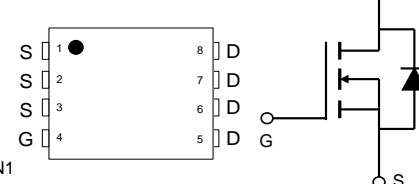
100% UIS Tested  
100%  $R_g$  Tested



**DFN5X6**



**Top View**



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AONS36344	DFN 5x6	Tape & Reel	3000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	83	A
$T_C=100^\circ C$		52	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	205	
Continuous Drain Current	$I_{DSM}$	33	A
$T_A=70^\circ C$		26	
Avalanche Current <sup>C</sup>	$I_{AS}$	64	A
Avalanche energy $L=0.01mH$ <sup>C</sup>	$E_{AS}$	20	mJ
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	V
Power Dissipation <sup>B</sup>	$P_D$	36	W
$T_C=25^\circ C$		14	
Power Dissipation <sup>A</sup>	$P_{DSM}$	5.6	W
$T_A=70^\circ C$		3.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	18	22	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		40	55	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	2.8	3.5	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.4	1.8	2.2	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		2.73	3.28	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		3.55	4.35	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		4	5.15	$\text{m}\Omega$
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	0.7	1	1	V
$I_S$	Maximum Body-Diode Continuous Current				40	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		1320		pF
$C_{oss}$	Output Capacitance			350		pF
$C_{rss}$	Reverse Transfer Capacitance			54		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	0.7	1.5	2.3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		19	32	nC
$Q_g(4.5\text{V})$	Total Gate Charge			10	16	nC
$Q_{gs}$	Gate Source Charge			3.3		nC
$Q_{gd}$	Gate Drain Charge			3.6		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		8		ns
$t_r$	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			20		ns
$t_f$	Turn-Off Fall Time			3		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		11		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		17		nC

A. The value of  $R_{JJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{DSM}$  is based on  $R_{JJA} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{JJA}$  is the sum of the thermal impedance from junction to case  $R_{JUC}$  and case to ambient.

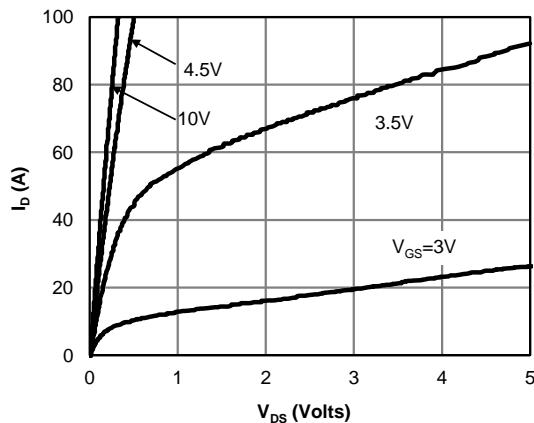
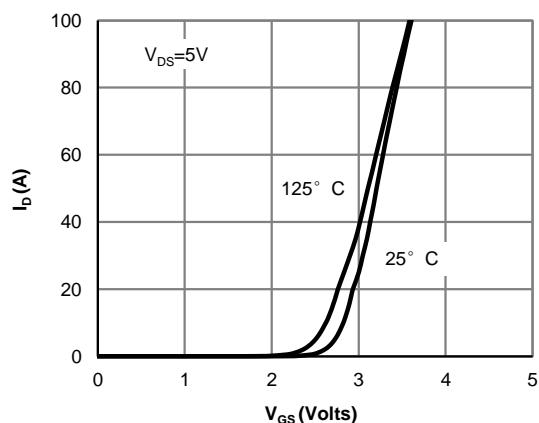
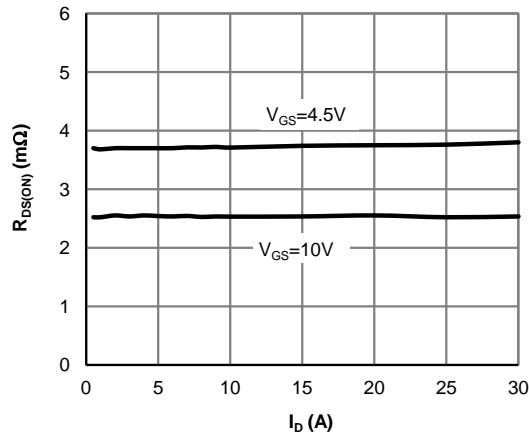
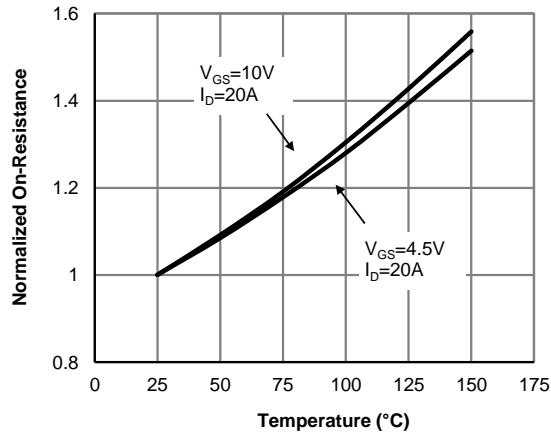
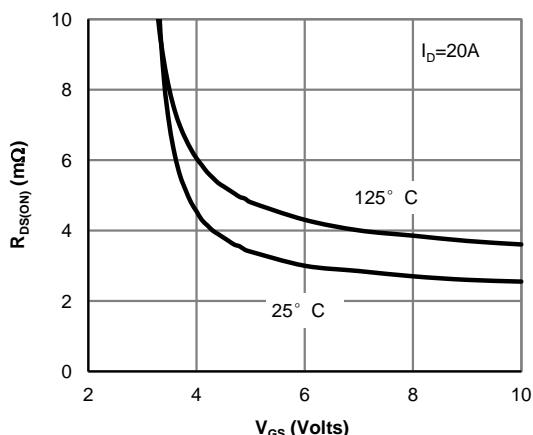
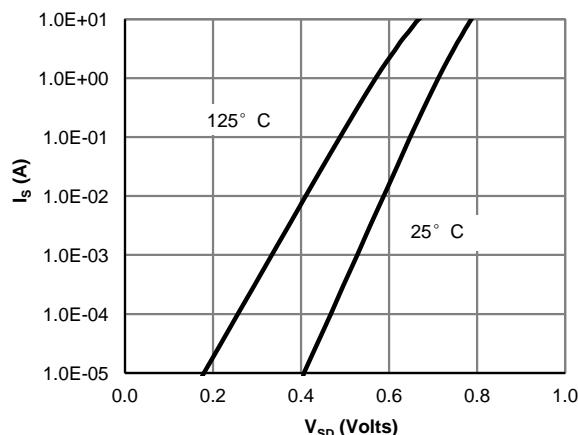
E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

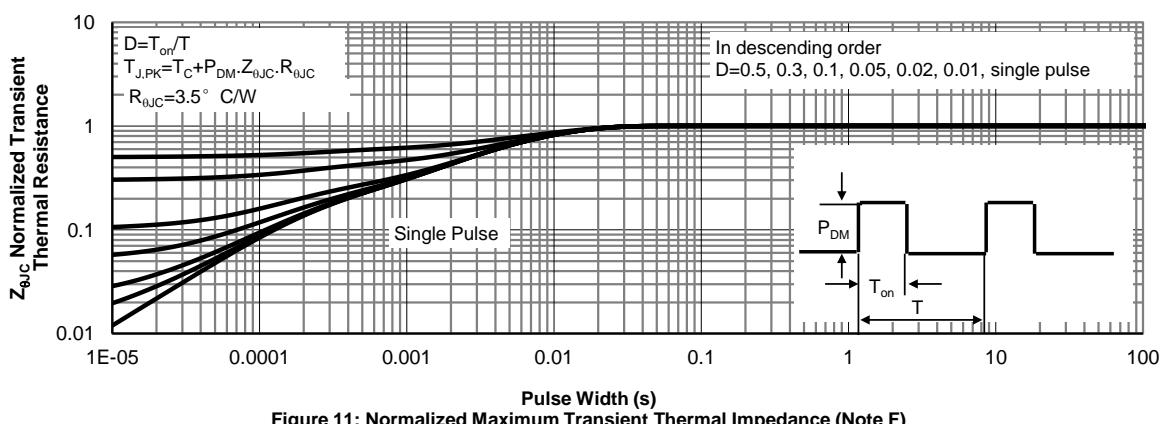
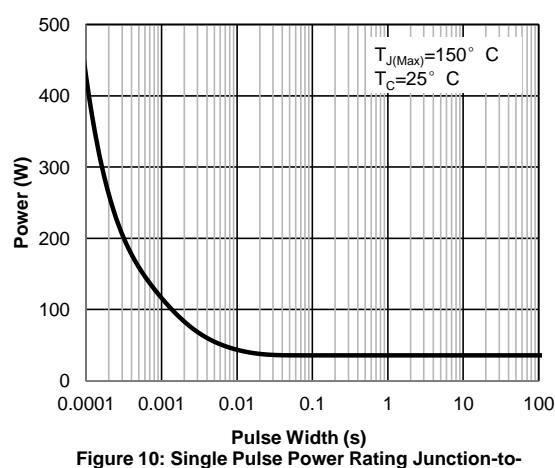
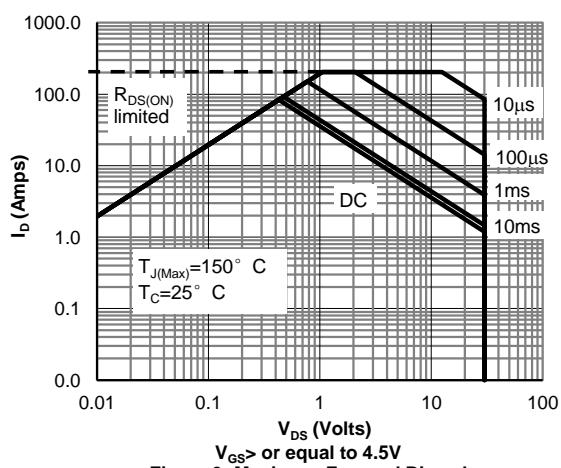
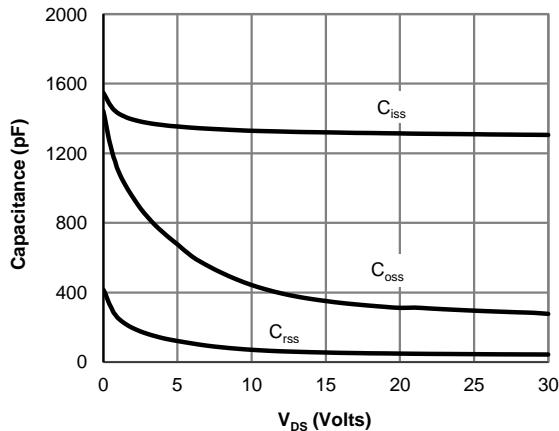
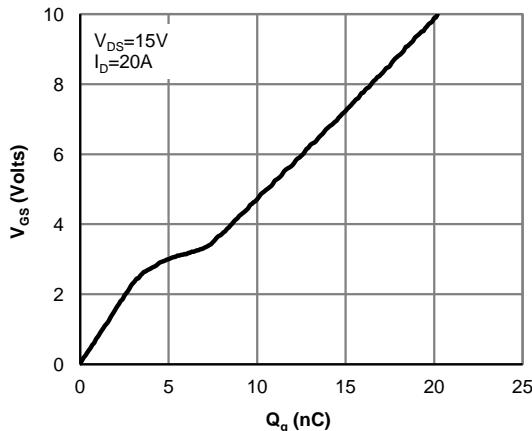
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

APPLICATIONS OR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


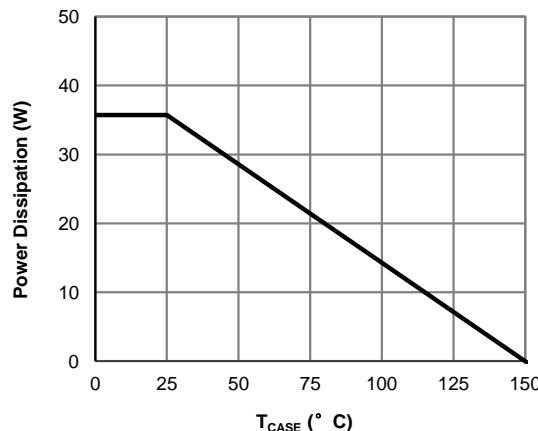
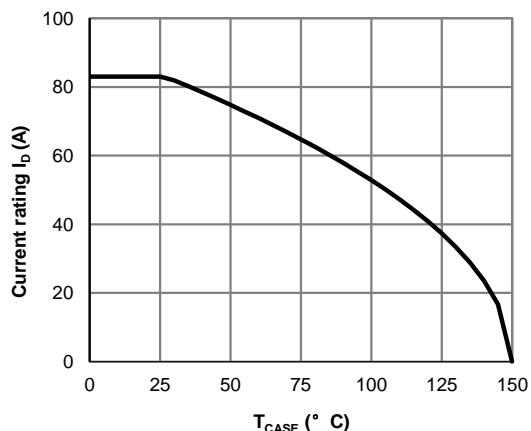
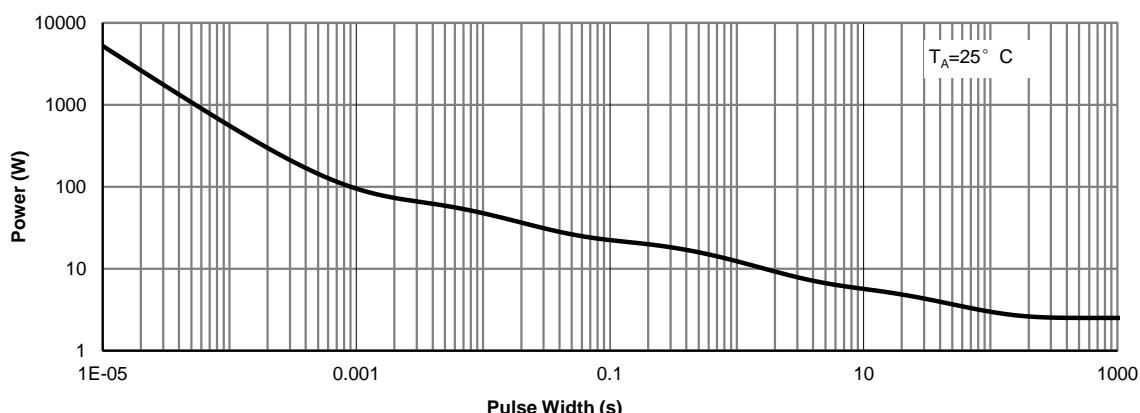
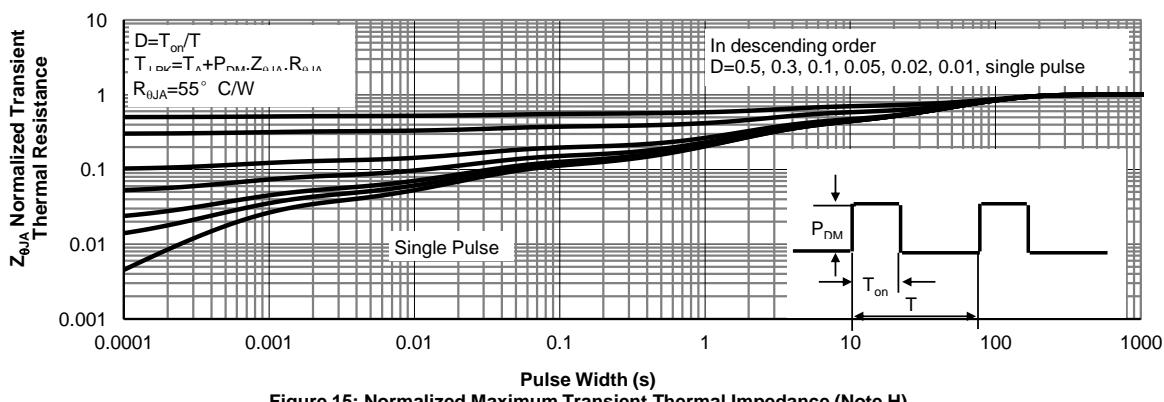
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 12: Power De-rating (Note F)**

**Figure 13: Current De-rating (Note F)**

**Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)**

**Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)**

Figure A: Gate Charge Test Circuit &amp; Waveforms

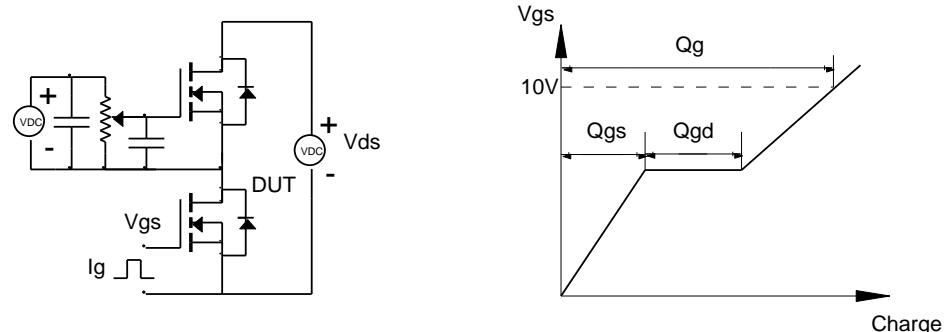


Figure B: Resistive Switching Test Circuit &amp; Waveforms

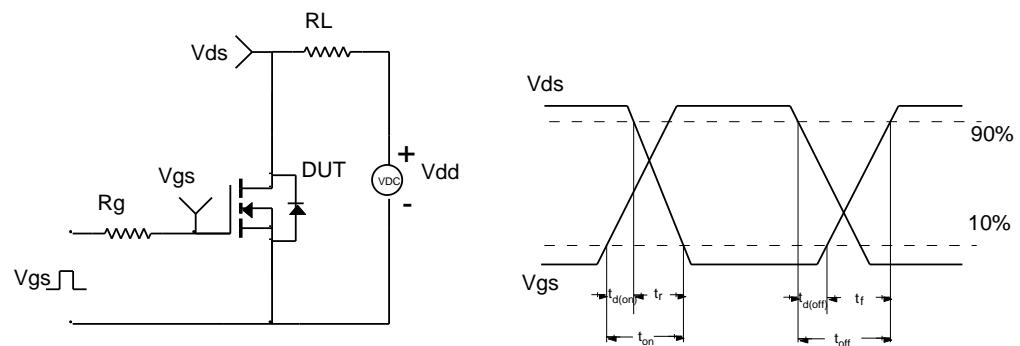


Figure C: Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms

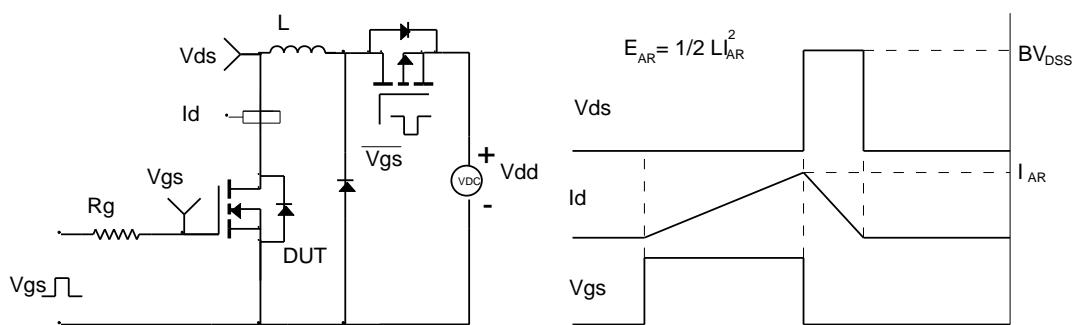


Figure D: Diode Recovery Test Circuit &amp; Waveforms

